Se	earcn	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/862,755	LI, YE
Examiner	Art Unit
Erin M. File	2634

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	340	12/21/2005	EMF

INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only— see search history printout)	12/21/2005	EMF
PALM Inventor Search	12/21/2005	EMF